

Ambient Particle Fallout Scanner

We help our customers to overcome today's cleanliness challenges in microtechnology. At Fastmicro, we believe you can accomplish breakthroughs in cleanliness control with fast, accurate and quantitative surface particle measurements.

Fastmicro enables process quality engineers to make reliable decisions on where and how to improve their cleanliness processes and deliver consistent quality products. And ultimately, achieve high equipment performance for their end users. To do this, we collaborate with the best to accomplish breakthroughs in cleanliness control.

Fallout Scanner for particle fallout measurements

The Fastmicro Fallout Scanner has been developed to measure the particle deposition rate in any industry. It can be used in both vacuum as well as ambient environments, and is typically used in clean environments.

The scanner module is also available as a white label solution for system integrators.

Continuously measure where and when it matters

The Fastmicro Fallout Scanner offers particle deposition rate monitoring with intervals in seconds.

The particle deposition rate can be accurately measured starting at particles of just 0.5 µm.

Combined with the easy to use software, we help our customers to view cleanliness measurements on surfaces instead of airborne-only. Not all particles remain airborne, as they could deposit on critical surfaces, impacting technical cleanliness.

With the Particle Fallout Scanner, the actual deposition rate becomes clear and can be used for further cleanliness improvement.

CONSISTENT MEASUREMENTS IN PROCESS

1. **Fast:** continuous monitoring in seconds
2. **Quantified:** fit for qualification and monitoring in production, as well as in an R&D environment
3. **Easy to operate:** operator independent
4. **Accurate:** high-resolution measurement (quantity, timestamp, position, size)
5. **Consistent:** objective measurements, time after time
6. **High throughput:** we enable high throughput



fastmicro
cleanliness control

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Specifications

Fast and

high production throughput

- Continuous monitoring of particle deposition on a surface with intervals of seconds

Data output

- Analysis: Quantity, Timestamp, Position and Size of particles
- Adder analysis: monitoring of incremental particle levels
- Annotated image with particle detection overlay, plus '3D' signal representation of any operator-selected particle
- Reporting: export function including KLARF and Excel Files (including standard bin sizes)
- Qualification report in UI and PDF, according to ISO standards 14644-9 and 14644-17

Easy to operate

- Operator independent

Detection range

- Detection limit from 0.5 μm PSL particles
- 90% cumulative particle count with PSL particles from 0.5 μm
- A Field of View of 1" diameter on a replaceable 2" diameter surface (25mm on 50mm)

Applicability

- Ambient environments
- Enabling workflow with follow-up analysis

Dimensions

- LxWxH: 405mm x 183mm x 209mm

Model

- FM-PS-PFS-V01
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Version: V3.1223



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